

Form PTO-1449
(Rev. 2-32)U.S. Department of Commerce
Patent & Trademark OfficeINFORMATION DISCLOSURE STATEMENT
(Use several sheets if necessary)Atty. Docket No.
005329 ALRT/MASK/RTSerial No.
UNKNOWNApplicant:
Shirley HEMAR et al.Filing Date:
Concurrently herewith

Group

J1017 U.S. PTO
09/876955

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Sub-Class	Filing Date (if appropriate)
JS	6,016,357	1/18/00	Neary et al.	382	144	1/16/97
JS	5,795,688	8/18/98	Burdorf et al.	430	30	8/14/96
JS	6,072,898	6/6/00	Beaty et al.	382	146	6/16/98
JS	6,148,097	11/14/00	Nakayama et al.	382	141	6/5/96
JS	6,075,883	6/13/00	Stern et al.	382	144	11/12/96
JS	6,025,905	2/15/00	Sussman	356	3.01	12/31/96
JS	6,052,478	4/18/00	Wihl et al.	382	144	10/9/96
JS	6,018,392	1/25/00	Tzu et al.	356	351	10/23/98
JS	6,081,659	6/27/00	Garza et al.	395	500.22	4/26/99
JS	6,078,738	6/20/00	Garza et al.	395	500.22	5/8/97

FOREIGN PATENT DOCUMENTS

Document	Date	Country	Class	Sub-class	Translation Yes/No
JS 0 628 806 A2	12/14/94	Europe			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

JS	Budd, Russell A., et al., "A New Tool for Phase Shift Mask Evaluation, the Stepper Equivalent Aerial Image Measurement System - AIMS TM ," SPIE Vol. 2087 Photomask Technology and Management (1993).
JS	Schenker, Richard, "Comparison of Single and Dual Exposure Phase Shift Mask Approaches for Poly Gate Patterning," SPIE, Vol. 3546, September 1998.

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U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Sub-Class	Filing Date (if appropriate)
JS	5,745,168	4/28/98	Ninomiya	348	191	
JS	5,744,381	4/28/98	Tabata et al.	438	16	
JS	5,481,624	1/2/96	Kamon	382	144	
JS	5,441,834	8/15/95	Takekuma et al.	430	5	
JS	5,272,116	12/21/93	Hosono	437	228	
JS	4,922,308	5/1/90	Noguchi et al.	356	237	
JS	4,148,065	4/3/79	Nakagawa et al.	358	101	
JS	5,572,598	11/5/96	Wihl et al.	382	144	
JS	6,091,845	7/18/00	Pierrat et al.	382	144	2/24/98

FOREIGN PATENT DOCUMENTS

Document	Date	Country	Class	Sub-class	Translation Yes/No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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